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Exploring the potential of transition metal tungstates for photoelectrochemical water oxidation: A combined experimental and computational approach

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Electronic Supplementary Information

Index

1. Materials.....	5
2. Digital pictures of the precursor solutions	5
3. Synthesis reactions	5
4. CuWO ₄ and FeWO ₄ Layers	6
5. DFT computational details.....	7
6. U _{eff} values used in PBE+U	7
7. Theoretical values for the indirect band gaps	7
8. SEM.....	8
9. EDS.....	10
10. XRD	12
11. Tests to discard the presence of significant amounts of WO ₃ on FeWO ₄	13
12. Band gaps	14
13. Flat bands potentials	14
14. Thickness and Photoresponse	21
15. Theoretical band edge energies	22
16. Comparison with literature	23
17. LSV at different light irradiances	24
18. Electrolyte-Electrode (EE) illumination	24
19. CuWO ₄ electron lifetime estimate.....	24
20. IPCE and APCE	25
21. Chronoamperometry at different pH values	27
10. Bibliography.....	27

Electronic Supplementary Information

Table of Figures

Figure S1. Precursor solutions of the Mn, Fe, Co, Ni, Cu and Zn tungstates.	5
Figure S2. LSVs for CuWO ₄ (a) and FeWO ₄ (b) electrodes with different numbers of layers, and a graphical representation of the current density of those samples at 1.23V vs. RHE (c and d, respectively).	6
Figure S3. SEM top-view of (a) Mn, (b) Fe, (c) Co, (d) Ni, (e) Cu and (f) Zn tungstate films.	8
Figure S4. Particle size histograms for (a) Cu and (b) Fe tungstate films.	9
Figure S5. EDS pictures of all the analyzed elements together, R-element and tungsten (from left to right) for all the RWO ₄ (from Mn to Zn).	11
Figure S6. XRD for the RWO ₄ tungstates (powder) and their identification cards. A) MnWO ₄ , B) FeWO ₄ , C) CoWO ₄ , D) NiWO ₄ , E) CuWO ₄ and F) ZnWO ₄	12
Figure S7. XRD for the RWO ₄ tungstates (thin films) and their identification cards. A) MnWO ₄ , B) FeWO ₄ , C) CoWO ₄ , D) NiWO ₄ , E) CuWO ₄ and F) ZnWO ₄ . FTO peaks labeled with blue open circles.	12
Figure S8. (a) CVs in the dark for N ₂ -purged 1 M HClO ₄ . (b) LSV in 0.2 M KPi for FeWO ₄ samples before and after being immersed for 5 min in a 0.02 M KOH solution.	13
Figure S9. Mott-Schottky (MS) plots for RWO ₄ electrodes (R = Mn, Fe, Co, Ni, Cu and Zn) in 0.1 M KPi.	16
Figure S10. MS plot for a CuWO ₄ electrode both under illumination (100 mW cm ⁻²) and in the dark.	17
Figure S11. Steady-state OCP at different light intensities for CuWO ₄	20
Figure S12. LSV for RWO ₄ electrodes in 0.1 M Na ₂ SO ₄ under 1 W cm ⁻² chopped illumination for the complete tungstate series: a) Mn, b) Fe, c) Ni, d) Cu and f) Zn. The grey dotted lines indicate the E _{fb} value	21
Figure S13. LSVs for RWO ₄ electrodes with the thickness of Table S7 in phosphate buffer solution (pH 7) both in the dark (dashed lines) and under 100 mW cm ⁻² SE illumination (solid lines) (Ni, Zn, and Co curves are given in the inset). CuWO ₄ has the same photocurrent as in Figure 7a because the thickness is the optimal.	22
Figure S14. (a), (b) LSVs at 0.1 and 1 W cm ⁻² for FeWO ₄ and CuWO ₄ electrodes, respectively. Broken curves were recorded in the dark.	24
Figure S15. LSV in 0.1 M Na ₂ SO ₄ by EE illumination of the electrodes under 100 mW cm ⁻² , for Fe and Cu tungstates. Continuous lines under irradiation and broken ones in the dark.	24
Figure S16. (a) OCP with light chopped on (-350 s) and off (0 s), (b) CV in the dark at 20 mV s ⁻¹ , (c) electron density (n _{ph}) vs. time, (d) electron lifetime (τ) vs. time (during potential relaxation). All these plots are for a CuWO ₄ electrode in an N ₂ purged 0.2 M KPi buffer solution.	25
Figure S17. Short-circuit photocurrent density from IPCE values for a) CuWO ₄ and b) FeWO ₄	26
Figure S18. Chronoamperometric curves for CuWO ₄ and FeWO ₄ electrodes at 1.23 V _{RHE} for different media: 0.1 M H ₂ SO ₄ (pH 1), 0.1 M KOH (pH 13.5), 0.2 M KPi (pH 7), and 0.1 M KBi (pH 9). *KBi stands for buffer borate, and KPi for buffer phosphate.	27

Electronic Supplementary Information

List of Tables

<i>Table S1. U_{eff} values used in PBE+U for the different elements that compose the tungstates.</i>	<i>7</i>
<i>Table S2. Indirect Band gap (E^{ind}_g) obtained from the band structure.</i>	<i>7</i>
<i>Table S3. Summary of the crystal size in the tungstate thin films from the full width at half maximum of the main XRD peaks.</i>	<i>13</i>
<i>Table S4. Direct and indirect band gaps, E_{gDir} and E_{gIn} obtained experimentally and theoretically (PBE+U) as well as values reported in the literature (E_{gBib}).</i>	<i>14</i>
<i>Table S5. E_{fb} as obtained by determining onset potentials with chopped illumination in 0.2M KPi and values reported in the literature.</i>	<i>14</i>
<i>Table S6. Mott-Schottky data obtained by Nyquist plots fitting with Z-view software.</i>	<i>18</i>
<i>Table S7. Film thickness of RWO_4 samples.</i>	<i>22</i>
<i>Table S8. Comparison of RWO_4 electrode related information in this work and in the bibliography, the irradiation power in all cases is 100 mW cm^{-2}.</i>	<i>23</i>

Electronic Supplementary Information

1. Materials

Citric acid monohydrate ($C_6H_8O_7 \cdot H_2O$; 99% from VWR) and cobalt (II) nitrate hexahydrate ($Co(NO_3)_2 \cdot 6H_2O$; 99.99% from VWR); ammonium (meta)tungstate hydrate (AMT) ($H_{43}N_6O_{41}W_{12}$; 99% from Indagoo); manganese (II) nitrate tetrahydrate ($Mn(NO_3)_2 \cdot 4H_2O$; 97% Merk) and copper (II) nitrate trihydrate ($Cu(NO_3)_2 \cdot 3H_2O$; 99.99% Merk); nickel (II) nitrate hexahydrate ($Ni(NO_3)_2 \cdot 6H_2O$; $\geq 98.5\%$ Fluka) and zinc nitrate hexahydrate ($Zn(NO_3)_2 \cdot 6H_2O$; 98% Fluka); iron (II) chloride tetrahydrate ($FeCl_2 \cdot 4H_2O$; 98% Thermo Scientific) and 2-methoxyethanol ($C_3H_8O_2$; 99% Thermo Scientific).

2. Digital pictures of the precursor solutions

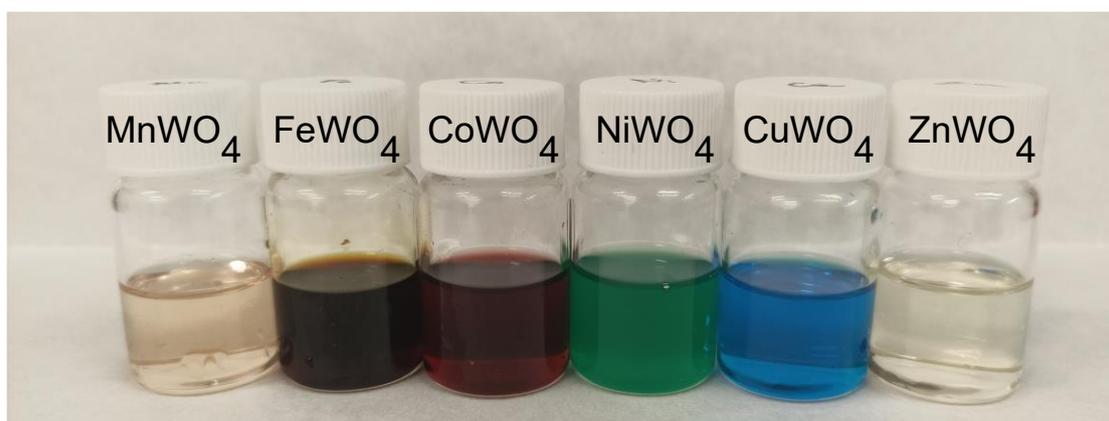
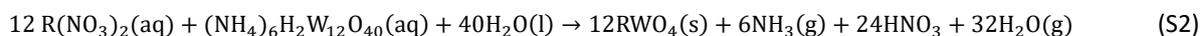


Figure S1. Precursor solutions of the Mn, Fe, Co, Ni, Cu and Zn tungstates.

3. Synthesis reactions

Synthesis reactions **Eq. S1** and **S2**:



Electronic Supplementary Information

4. CuWO_4 and FeWO_4 Layers

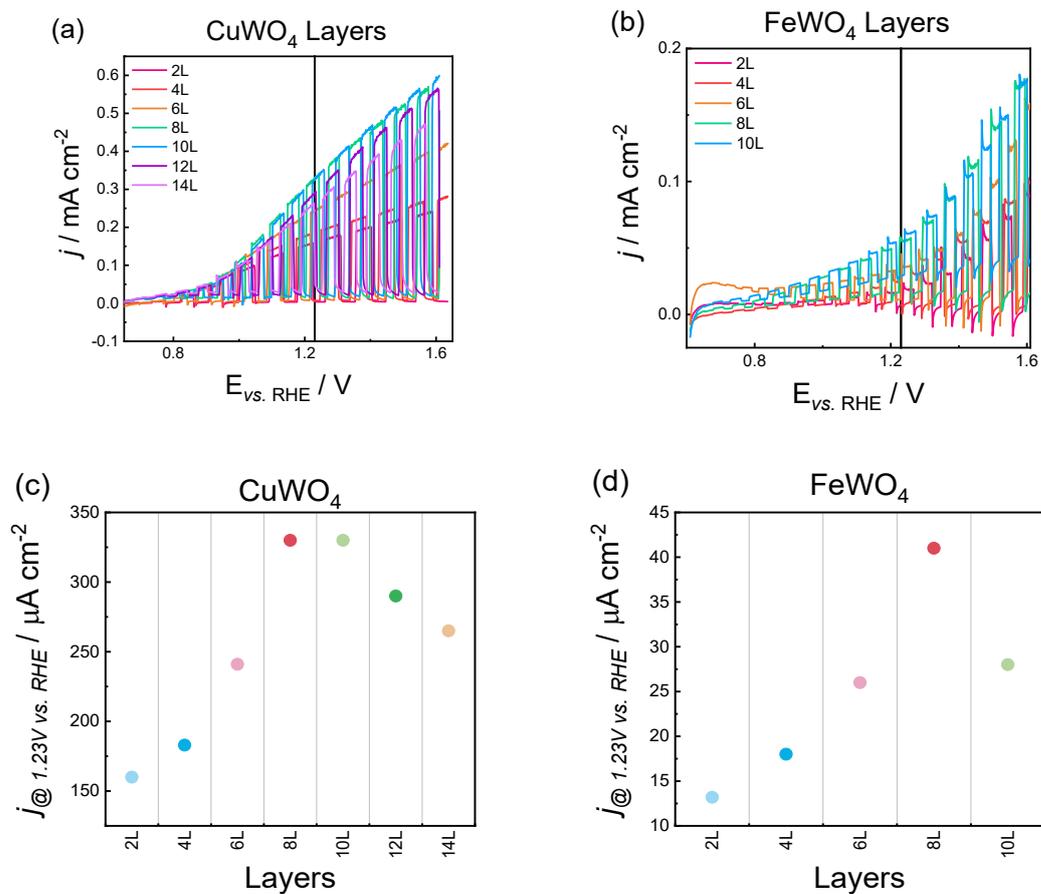


Figure S2. LSVs for CuWO_4 (a) and FeWO_4 (b) electrodes with different numbers of layers, and a graphical representation of the current density of those samples at 1.23V vs. RHE (c and d, respectively).

Electronic Supplementary Information

5. DFT computational details

The structures extracted from the Crystallographic Open Database (COD) were subject to calculations for: a) evaluating the ferro/antiferromagnetic behavior, b) optimizing the geometry, and c) obtaining the DOS profile.

The ferro/antiferromagnetic calculations have been carried out with a k-point density per unit cell of 500, an electronic convergence criterion of $1 \cdot 10^{-4}$ eV. The geometry optimization was done with an electronic convergence criterion of $1 \cdot 10^{-6}$ eV, a geometric convergence criterion of forces below $0.01 \text{ eV} \cdot \text{\AA}^{-1}$ and a k-point density per unit cell of 1500. For obtaining the DOS profiles, a single-point calculation was performed with an electronic convergence criterion of $1 \cdot 10^{-8}$ eV and a k-point density per unit cell of 15000.

The Boltztrap 2 code was used to get the effective masses of the charge carriers from the PBE+U electronic structure.¹ These effective masses have been estimated from a parabolic band model (Eq. S3).

$$E(k) = E_0 + \frac{\hbar^2 k^2}{2m^*} \quad (\text{S3})$$

where m^* is the effective mass of the electrons/holes in the band, $E(k)$ is the energy of an electronic state with wavevector k (describes the electron momentum in the reciprocal space), E_0 is the band-edge energy (minimum energy of the conduction band or maximum energy of the valence band), and \hbar is the reduced Planck's constant.

6. U_{eff} values used in PBE+U

Table S1. U_{eff} values used in PBE+U for the different elements that compose the tungstates.

Element	W	Mn	Fe	Co	Ni	Cu	Zn
$U_{\text{eff}} / \text{eV}$	4.0	3.0	3.0	2.8	5.0	6.7	4.0

7. Theoretical values for the indirect band gaps

Table S2. Indirect Band gap ($E_{\text{g}}^{\text{Ind}}$) obtained from the band structure.

Material	Transition	$E_{\text{g}}^{\text{Ind}} / \text{eV}$
MnWO ₄	D→M	2.38
FeWO ₄	X→Z	1.44
CoWO ₄	Γ→Z	2.11
NiWO ₄	R → Γ	2.95
CuWO ₄	Γ → L	2.04
ZnWO ₄	Γ-Z→ Y	2.76

8. SEM

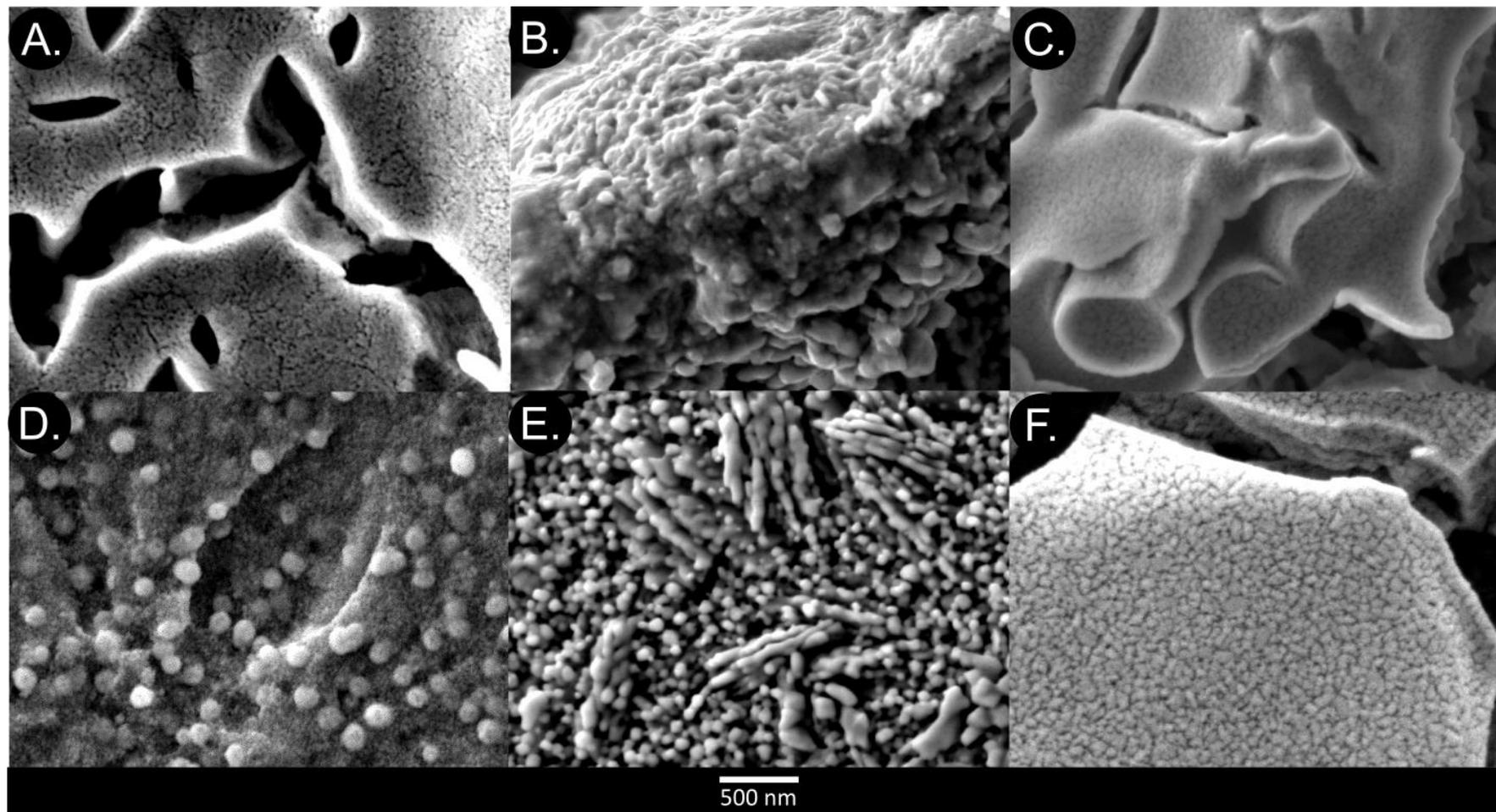
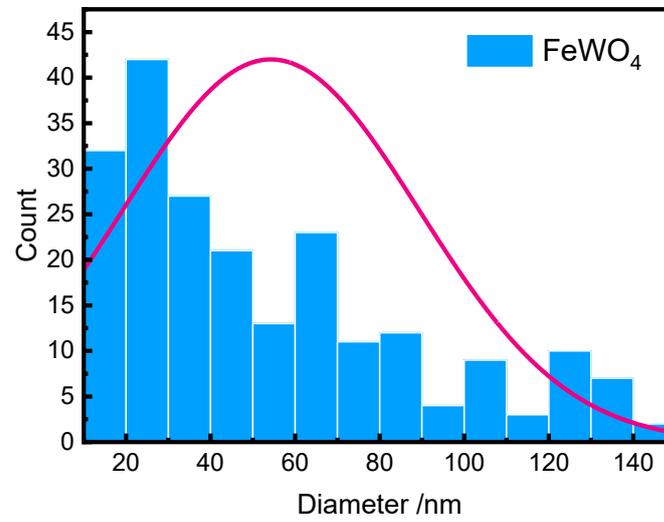


Figure S3. SEM top-view of (a) Mn, (b) Fe, (c) Co, (d) Ni, (e) Cu and (f) Zn tungstate films.

Electronic Supplementary Information

a)



b)

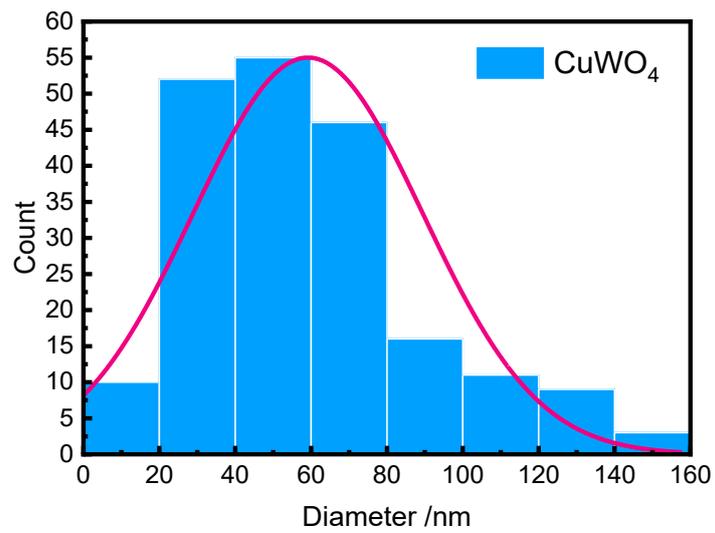
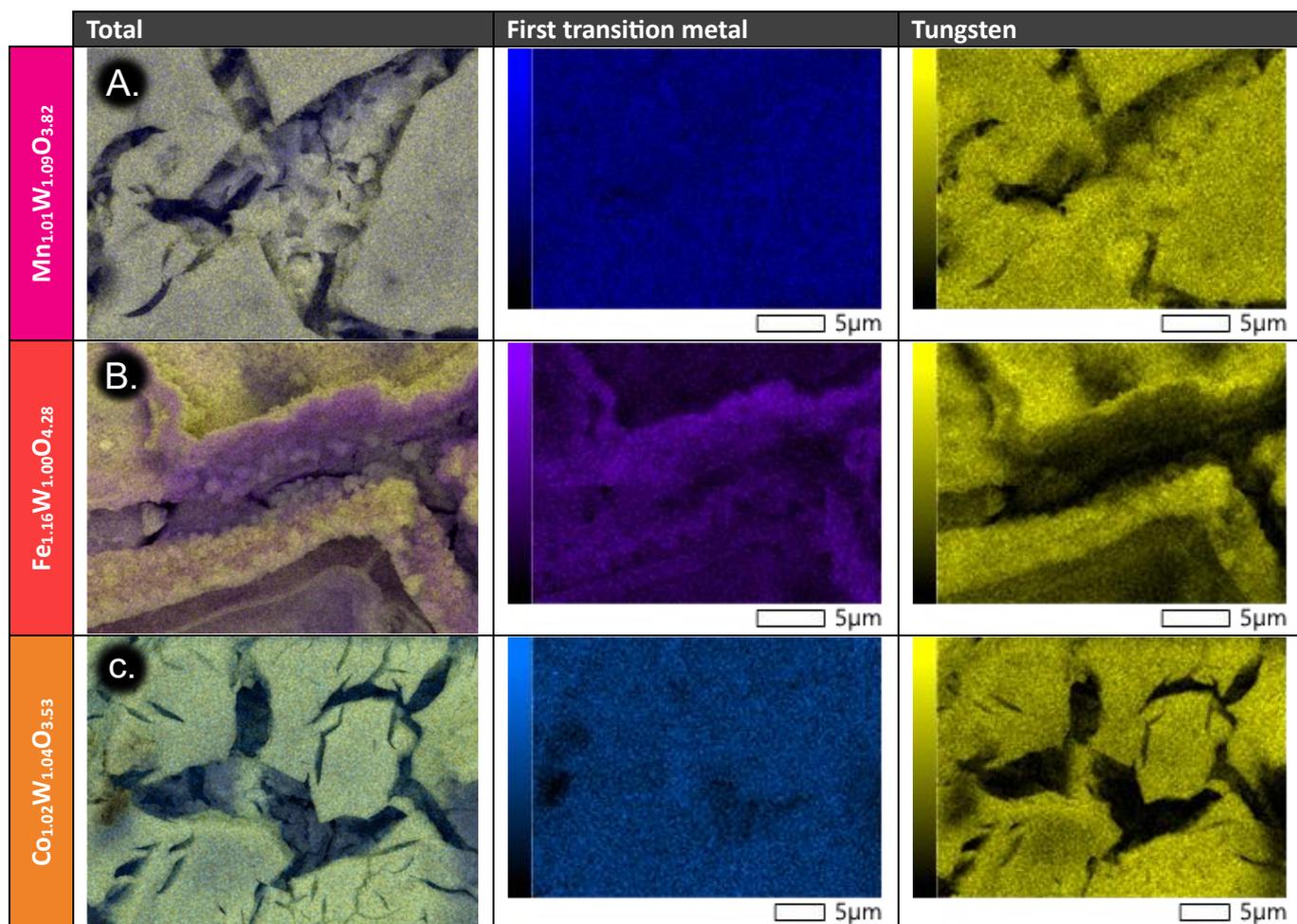


Figure S4. Particle size histograms for (a) Cu and (b) Fe tungstate films.

Electronic Supplementary Information

9. EDS



Electronic Supplementary Information

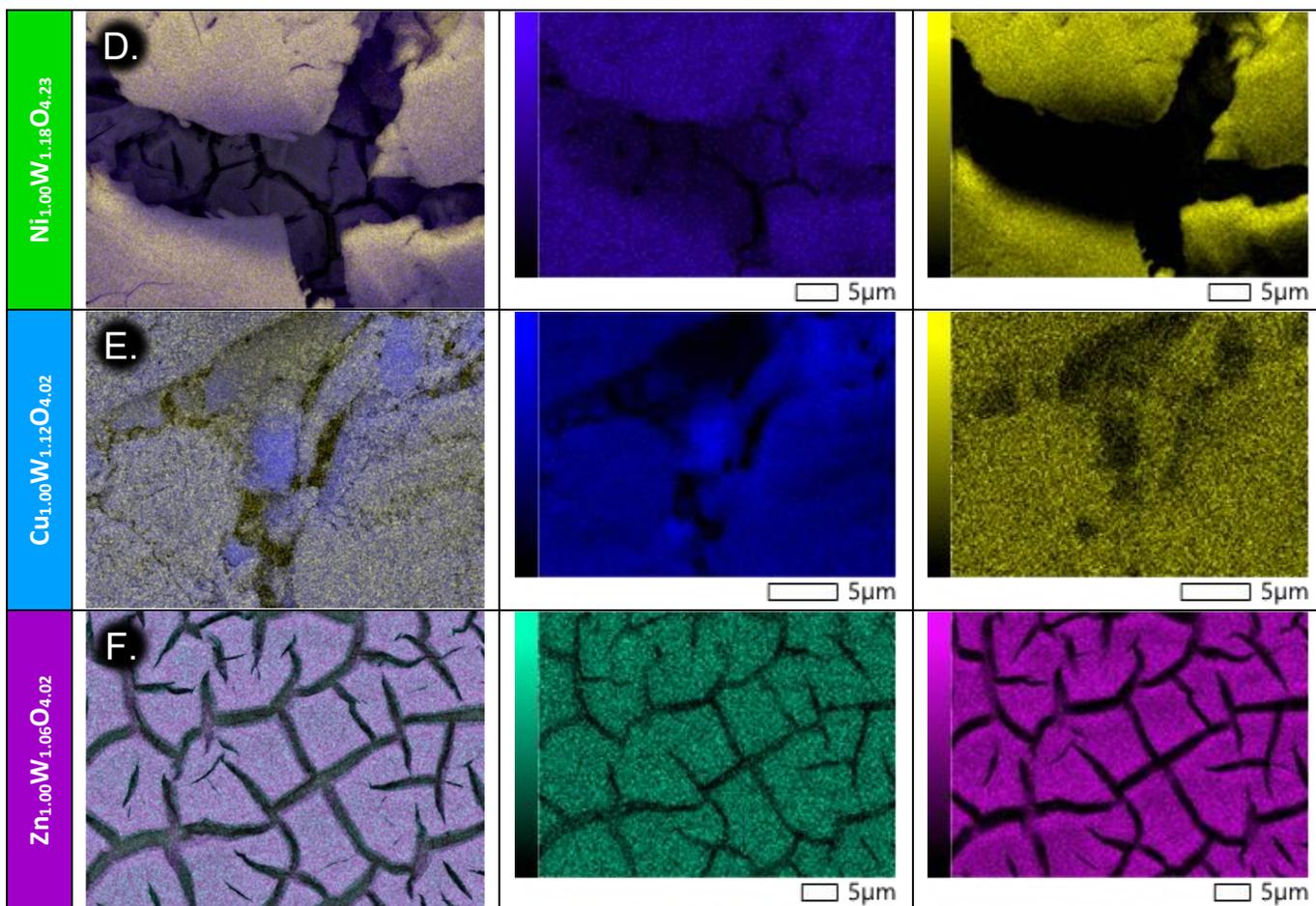


Figure S5. EDS pictures of all the analyzed elements together, R-element and tungsten (from left to right) for all the RWO₄ (from Mn to Zn).

Electronic Supplementary Information

10. XRD

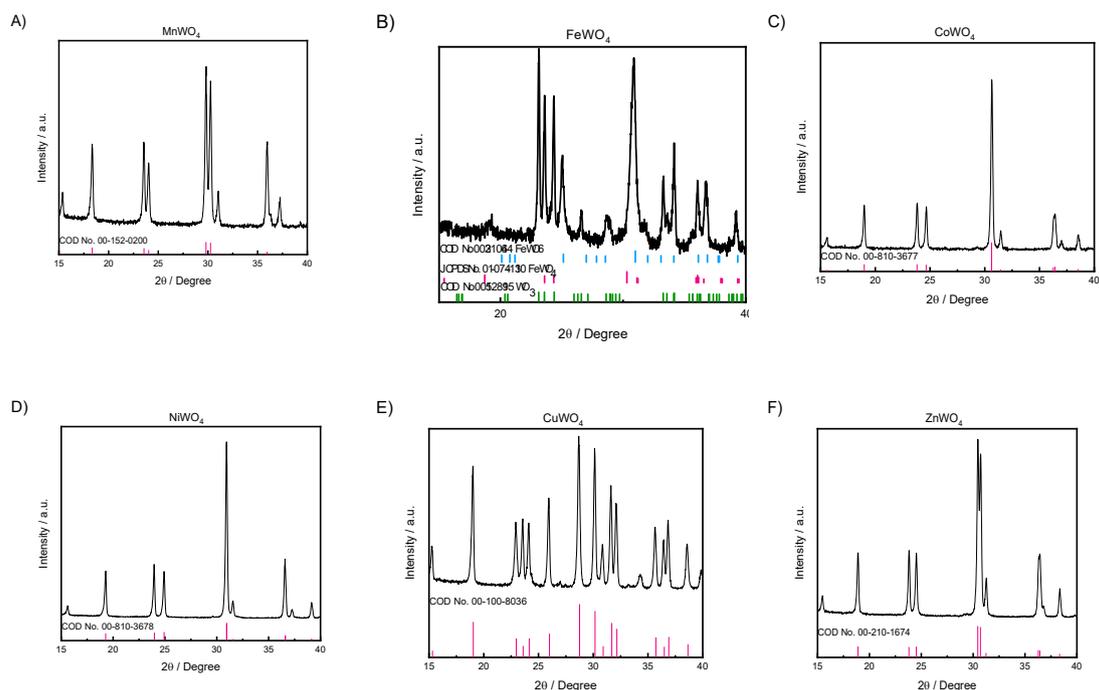


Figure S6. XRD for the RWO_4 tungstates (powder) and their identification cards. A) $MnWO_4$, B) $FeWO_4$, C) $CoWO_4$, D) $NiWO_4$, E) $CuWO_4$ and F) $ZnWO_4$.

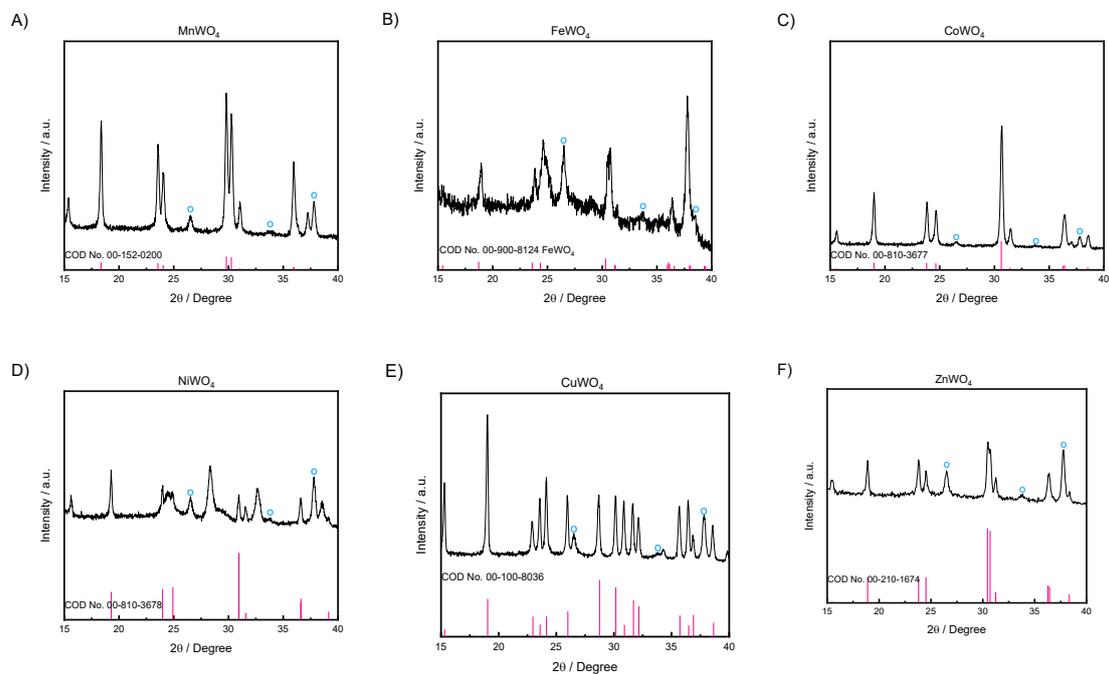


Figure S7. XRD for the RWO_4 tungstates (thin films) and their identification cards. A) $MnWO_4$, B) $FeWO_4$, C) $CoWO_4$, D) $NiWO_4$, E) $CuWO_4$ and F) $ZnWO_4$. FTO peaks labeled with blue open circles.

Electronic Supplementary Information

The diffractograms in Figure S6. XRD for the RWO_4 tungstates (powder) and their identification cards. A) MnWO_4 , B) FeWO_4 , C) CoWO_4 , D) NiWO_4 , E) CuWO_4 and F) ZnWO_4 . and S7 are similar for most of the samples, except for FeWO_4 and NiWO_4 . In the FeWO_4 case and in contrast with the corresponding powders, neither WO_3 nor Fe(III)-related impurities were detected in the thin film. This could result from the role of FTO as a heterogeneous nucleation surface, which could favor the growth of FeWO_4 over that of the impurities.

The Scherrer equation (Eq S4) was employed to obtain an average crystal size for the different samples.

$$D = \frac{K\lambda}{\beta \cos\theta} \quad (\text{S4})$$

where D is the crystal size (nm), K is the Scherrer constant (0.9), λ is the wavelength of the X-ray source (0.15406 nm), β is the full width at half maximum (FWMH), and θ is the Bragg angle of the peak.

The most significant peaks in the diffractograms were used to obtain the crystal size (Table S3), which is similar for all the samples, except for ZnWO_4 . It seems thus that the crystal size of the samples is not key for explaining the observed differences in the photoelectrochemical responses.

Table S3. Summary of the crystal size in the tungstate thin films from the full width at half maximum of the main XRD peaks.

Sample	2θ / degrees	FWHM / degrees	Crystallite size /nm
MnWO_4	30	0.34	27
FeWO_4	38	0.40	23
CoWO_4	31	0.40	23
NiWO_4	20	0.42	22
CuWO_4	19	0.40	23
ZnWO_4	31	1.00	9

Electronic Supplementary Information

11. Tests to discard the presence of significant amounts of WO₃ on FeWO₄

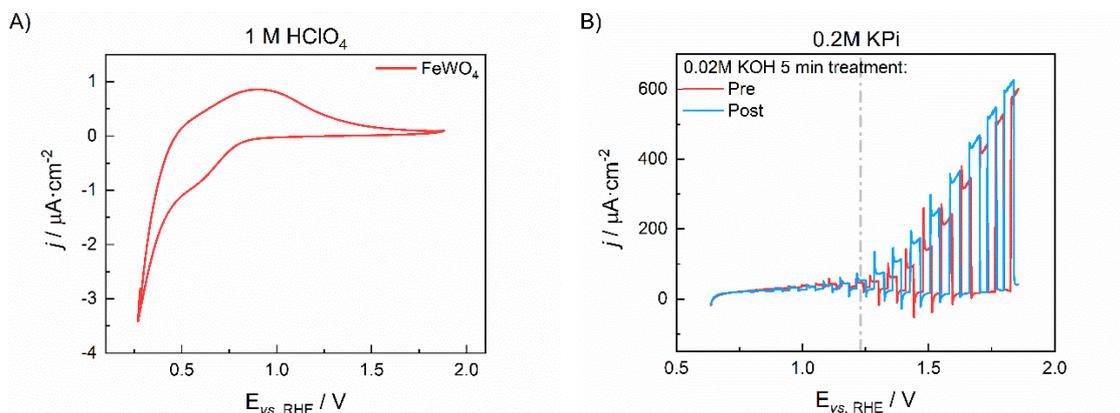


Figure S8. (a) CVs in the dark for N₂-purged 1 M HClO₄. (b) LSV in 0.2 M KPi for FeWO₄ samples before and after being immersed for 5 min in a 0.02 M KOH solution.

The FeWO₄ dark CV (**Figure S8a**) is rather different from that of WO₃ under the same conditions.² More significantly, **Figure S8.** (a) CVs in the dark for N₂-purged 1 M HClO₄. (b) LSV in 0.2 M KPi for FeWO₄ samples before and after being immersed for 5 min in a 0.02 M KOH solution.

b shows LSVs for FeWO₄ before and after being treated for 5 min in a 0.02 M KOH solution. The photocurrents at 1.23 V vs. RHE (and in the whole potential range) are similar in both cases. As any surface WO₃ would be dissolved in the alkaline solution, this result supports the fact that WO₃ is absent from the surface of as-prepared FeWO₄ thin films.

12. Band gaps

Table S4. Direct and indirect band gaps, E_g^{Dir} and E_g^{In} obtained experimentally and theoretically (PBE+U) as well as values reported in the literature (E_g^{Bib}).

Sample	E _g ^{Dir-Exp} / eV	E _g ^{In-Exp} / eV	E _g ^{Bib-Exp} / eV		E _g ^{Exp-DFT} / eV	E _g ^{Bib-DFT} / eV
			Direct	Indirect		
MnWO ₄	2.90	2.84	2.70-2.88 ³⁻⁵	2.63 ⁶	2.38	2.40 ⁷
FeWO ₄	1.96	1.89	1.70-2.16 ^{4,8,9}	1.95 ¹⁰	1.44	2.00 ¹¹
CoWO ₄	2.90	2.78	2.70-2.86 ¹²⁻¹⁴	2.25 ¹⁵	2.11	2.33 ¹⁵
NiWO ₄	3.22	3.13	2.80-3.67 ¹⁶⁻¹⁸	2.25 ¹⁹	2.95	2.7 ²⁰
CuWO ₄	2.57	2.37	2.32-2.74 ^{21,22}	2.37 ^{23,24}	2.04	2.27 ²⁰
ZnWO ₄	3.81	3.73	3.88 ²⁵	2.67 ²⁶	2.76	3.77 ²⁷

13. Flat bands potentials

Table S5. E_{fb} as obtained by determining onset potentials with chopped illumination in 0.2M KPi and values reported in the literature.

	Flat band / V _{RHE}	Reported
MnWO ₄	0.88 V	0.98 ²⁸

Electronic Supplementary Information

FeWO₄	0.50 V	0.73 ²⁹
CoWO₄	0.58 V	0.47 ³⁰
NiWO₄	0.55 V	0.48 ³¹
CuWO₄	0.60 V (0.5 in MS, 0.65 in OCP)	0.65 ³²
ZnWO₄	0.55	0.20 ³³

Different methods were followed to obtain the flat band potentials of RWO₄. These approaches were:

i. Mott-Schottky

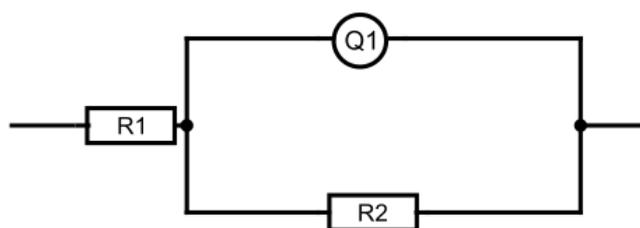
Mott-Schottky (MS) plots were obtained by performing Electrochemical Impedance Spectroscopy measurements at frequencies ranging from 10⁵ Hz to 0.1 Hz with an amplitude of 10 mV and at applied potentials from 0.74 to 1.64 V_{RHE}. Bode and Nyquist plots were recorded for each potential and RWO₄.

This method allows for the determination of the flat band potential by measuring the differential capacitance of the semiconductor-electrolyte interface. The Mott-Schottky equation (Eq. S5) for an n-type material is:

$$\frac{1}{C_{sc}^2} = \frac{2}{\epsilon_0 \epsilon_r e n} \left(E - E_{fb} - \frac{k_b T}{e} \right) \quad (S5)$$

Where C_{sc} is the capacitance, ϵ_0 is the vacuum permittivity, ϵ_r the dielectric constant of the semiconductor, e the elementary charge, n the density of donors, E the applied electrode potential, E_{fb} the flat band potential, k_b the Boltzmann constant and T the temperature.

The equivalent circuit used for obtaining the Mott-Schottky capacitance values is depicted in **Scheme S1**.



Scheme S1. Equivalent circuit for CuWO₄. Being R the elements for resistance, and Q the CPE (constant phase element).

This circuit was applied to each Nyquist plot with the Z-view software. Resistance and CPE parameters were obtained. To estimate C_{sc} from the CPE, eqs. S6-8 were applied:

$$C_{sc} = Q \cdot (\omega_{max})^{n-1} \quad (S6)$$

Electronic Supplementary Information

$$\omega_{max} = \left(\frac{1}{R_2 \cdot Q}\right)^{1/n} \quad (S7)$$

$$C_{SC} = Q^{1/n} \cdot R_2^{\frac{1-n}{n}} \quad (S8)$$

where Q is the CPE constant, n the CPE exponent, ω the frequency, and R the resistance.

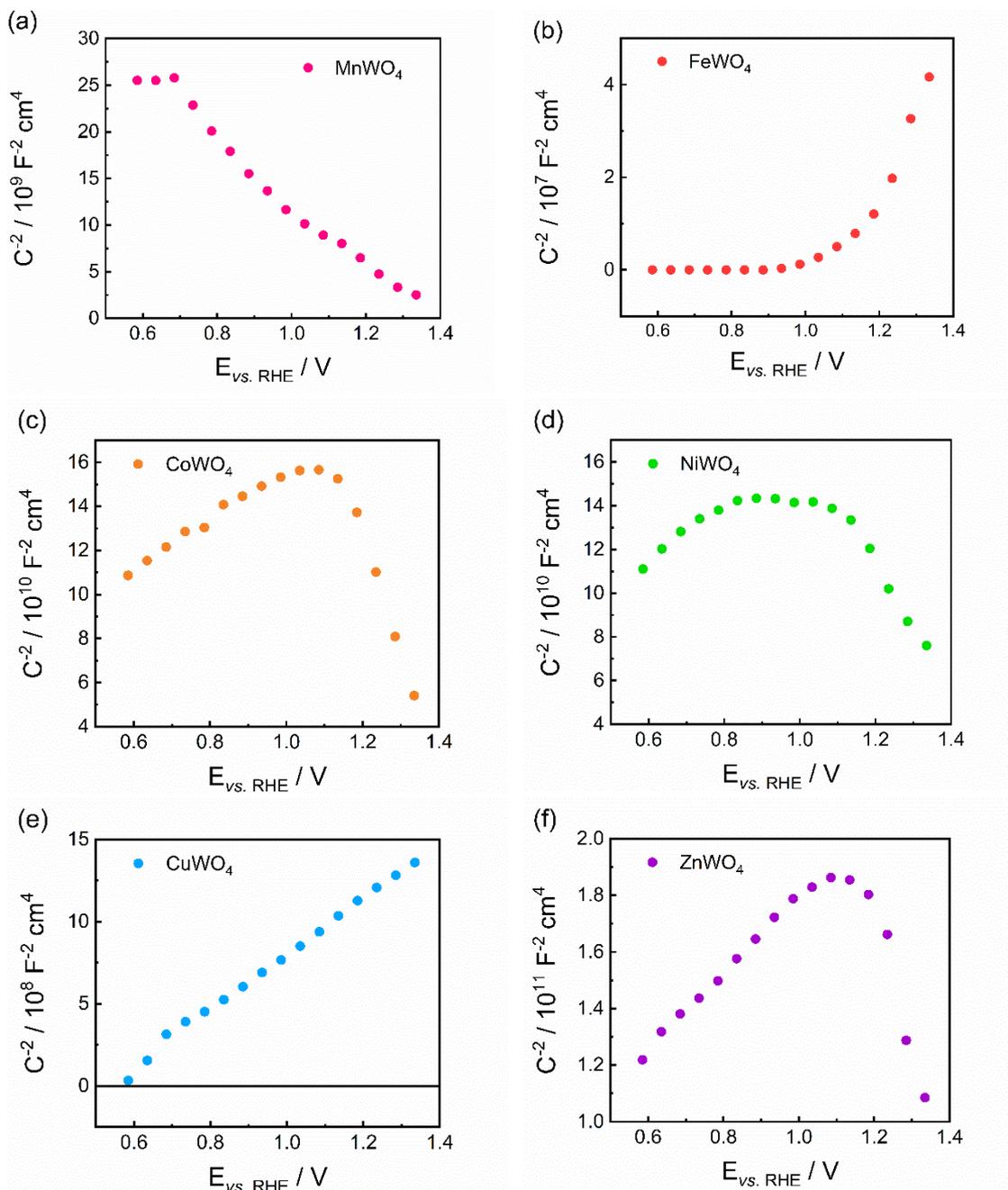


Figure S9. Mott-Schottky (MS) plots for RWO₄ electrodes (R = Mn, Fe, Co, Ni, Cu and Zn) in 0.1 M KPi.

To estimate the CuWO₄ donor density, Eq. S9 was used.

$$n_D = \frac{2}{\epsilon_0 \epsilon_r e m} \quad (S9)$$

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Here, n_D is the donor density (m^{-3}), ϵ_0 is the vacuum permittivity ($8.85 \cdot 10^{-12} \text{ F m}^{-1}$), ϵ_r is the dielectric constant of the material (83 for CuWO_4), e is the elementary charge ($1.60 \cdot 10^{-19} \text{ C}$), and m is the slope of the MS plot ($\text{F}^{-2} \text{ m}^4$). In our case, CuWO_4 has a donor density (n_D) of $9.7 \cdot 10^{20} \text{ cm}^{-3}$.

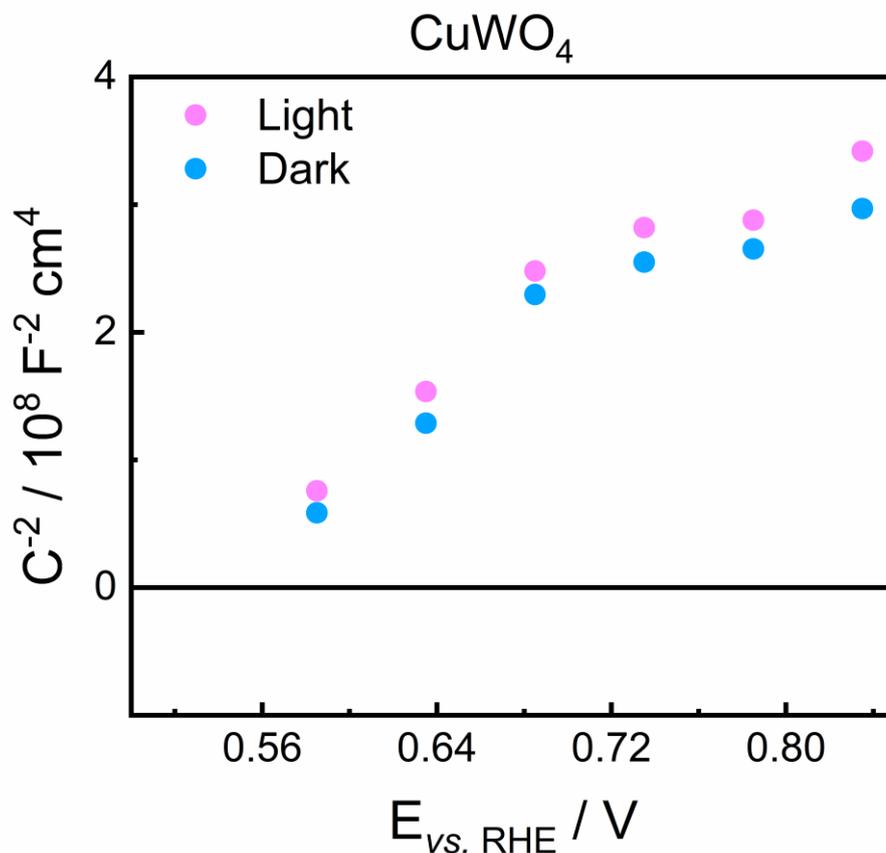


Figure S10. MS plot for a CuWO_4 electrode both under illumination (100 mW cm^{-2}) and in the dark.

As can be seen in Figure S10, CuWO_4 follows the BEP regime both under illumination and in the dark. Importantly, the MS plots are almost identical in both cases, which indicated that illumination does not cause band unpinning.

Electronic Supplementary Information

Table S6. Mott-Schottky data obtained by Nyquist plots fitting with Z-view software.

MnWO ₄															
E / V	-0.05	0	0.05	0.1	0.15	0.2	0.25	0.3	0.35	0.4	0.45	0.5	0.55	0.6	0.65
R₂/Ω	2.7·10 ⁰⁴	2.7·10 ⁰⁴	3.0·10 ⁰⁴	3.1·10 ⁰⁴	3.0·10 ⁰⁴	3.0·10 ⁰⁴	2.9·10 ⁰⁴	2.8·10 ⁰⁴	2.8·10 ⁰⁴	2.6·10 ⁰⁴	2.3·10 ⁰⁴	2.1·10 ⁰⁴	2.0·10 ⁰⁴	2.0·10 ⁰⁴	2.0·10 ⁰⁴
Q/Ω⁻¹sⁿ	7.5·10 ⁻⁰⁶	7.5·10 ⁻⁰⁶	7.4·10 ⁻⁰⁶	7.8·10 ⁻⁰⁶	8.3·10 ⁻⁰⁶	8.8·10 ⁻⁰⁶	9.4·10 ⁻⁰⁶	1.0·10 ⁻⁰⁵	1.1·10 ⁻⁰⁵	1.2·10 ⁻⁰⁵	1.3·10 ⁻⁰⁵	1.4·10 ⁻⁰⁵	1.5·10 ⁻⁰⁵	1.8·10 ⁻⁰⁵	2.1·10 ⁻⁰⁵
n	0.90	0.90	0.90	0.90	0.89	0.89	0.89	0.89	0.88	0.87	0.86	0.85	0.84	0.83	0.82
FeWO ₄															
R₂/Ω	1.0·10 ⁺² 0	1.0·10 ⁺²⁰	1.0·10 ⁺²⁰	6.9·10 ⁺²⁰	1.1·10 ⁺¹⁸	5.5·10 ⁺¹¹	5.4·10 ⁺¹¹	2.8·10 ⁺⁰⁶	8.3·10 ⁺⁰⁵	5.0·10 ⁺⁰⁵	4.0·10 ⁺⁰⁵	3.7·10 ⁺⁰⁵	3.4·10 ⁺⁰⁵	3.0·10 ⁺⁰⁵	2.6·10 ⁺⁰⁵
Q/Ω⁻¹sⁿ	1.3·10 ⁻⁰³	9.3·10 ⁻⁰⁴	6.5·10 ⁻⁰⁴	5.2·10 ⁻⁰⁴	3.6·10 ⁻⁰⁴	2.8·10 ⁻⁰⁴	2.3·10 ⁻⁰⁴	1.9·10 ⁻⁰⁴	1.6·10 ⁻⁰⁴	1.4·10 ⁻⁰⁴	1.2·10 ⁻⁰⁴	9.9·10 ⁻⁰⁵	8.5·10 ⁻⁰⁵	7.4·10 ⁻⁰⁵	6.4·10 ⁻⁰⁵
n	0.82	0.83	0.81	0.81	0.76	0.75	0.74	0.74	0.74	0.74	0.74	0.74	0.73	0.74	0.74
CoWO ₄															
R₂/Ω	5.2·10 ⁺⁰ 4	4.1·10 ⁺⁰⁴	2.6·10 ⁺⁰⁴	5.5·10 ⁺⁰⁴	6.0·10 ⁺⁰⁴	5.7·10 ⁺⁰⁴	5.9·10 ⁺⁰⁴	5.8·10 ⁺⁰⁴	5.8·10 ⁺⁰⁴	5.8·10 ⁺⁰⁴	5.7·10 ⁺⁰⁴				
Q/Ω⁻¹sⁿ	3.3·10 ⁻⁰⁶	3.4·10 ⁻⁰⁶	3.7·10 ⁻⁰⁶	3.2·10 ⁻⁰⁶	3.1·10 ⁻⁰⁶	3.0·10 ⁻⁰⁶	3.0·10 ⁻⁰⁶	2.9·10 ⁻⁰⁶	3.1·10 ⁻⁰⁶	3.5·10 ⁻⁰⁶					
n	0.93	0.93	0.92	0.93	0.93	0.93	0.93	0.93	0.93	0.93	0.93	0.93	0.93	0.92	0.92
NiWO ₄															
R₂/Ω	3.1 ·10 ⁺⁰⁴	3.4·10 ⁺⁰⁴	3.8·10 ⁺⁰⁴	3.9·10 ⁺⁰⁴	4.0·10 ⁺⁰⁴	4.0·10 ⁺⁰⁴	4.1·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.1·10 ⁺⁰⁴	4.1·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.3·10 ⁺⁰⁴
Q/Ω⁻¹sⁿ	3.7·10 ⁻⁰⁶	3.5·10 ⁻⁰⁶	3.4·10 ⁻⁰⁶	3.3·10 ⁻⁰⁶	3.3·10 ⁻⁰⁶	3.2·10 ⁻⁰⁶	3.2·10 ⁻⁰⁶	3.2·10 ⁻⁰⁶	3.3·10 ⁻⁰⁶	3.3·10 ⁻⁰⁶	3.3·10 ⁻⁰⁶	3.4·10 ⁻⁰⁶	3.6·10 ⁻⁰⁶	4.0·10 ⁻⁰⁶	4.3·10 ⁻⁰⁶
n	0.91	0.91	0.91	0.91	0.91	0.91	0.91	0.91	0.90	0.90	0.90	0.90	0.89	0.88	0.88
CuWO ₄															
R₂/Ω	5.0·10 ⁺⁰ 3	8.9·10 ⁺⁰³	1.9·10 ⁺⁰⁴	3.3·10 ⁺⁰⁴	4.2·10 ⁺⁰⁴	4.7·10 ⁺⁰⁴	5.1·10 ⁺⁰⁴	5.3·10 ⁺⁰⁴	5.5·10 ⁺⁰⁴	5.6·10 ⁺⁰⁴	5.6·10 ⁺⁰⁴	5.7·10 ⁺⁰⁴	5.8·10 ⁺⁰⁴	6.0·10 ⁺⁰⁴	6.2·10 ⁺⁰⁴
Q/Ω⁻¹sⁿ	1.8·10 ⁻⁰⁴	8.5·10 ⁻⁰⁵	5.6·10 ⁻⁰⁵	4.8·10 ⁻⁰⁵	4.4·10 ⁻⁰⁵	4.0·10 ⁻⁰⁵	3.7·10 ⁻⁰⁵	3.5·10 ⁻⁰⁵	3.3·10 ⁻⁰⁵	3.1·10 ⁻⁰⁵	3.0·10 ⁻⁰⁵	2.8·10 ⁻⁰⁵	2.7·10 ⁻⁰⁵	2.6·10 ⁻⁰⁵	2.6·10 ⁻⁰⁵
n	0.76	0.84	0.89	0.89	0.89	0.88	0.87	0.87	0.86	0.85	0.85	0.84	0.84	0.84	0.83
ZnWO ₄															

Electronic Supplementary Information

R_2/Ω	$1.6 \cdot 10^{+0}$ 4	$3.7 \cdot 10^{+04}$	$8.1 \cdot 10^{+04}$	$1.2 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.4 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.4 \cdot 10^{+05}$	$1.4 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$	$1.3 \cdot 10^{+05}$
$Q/\Omega^{-1} s^n$	$3.5 \cdot 10^{-06}$	$3.2 \cdot 10^{-06}$	$2.9 \cdot 10^{-06}$	$2.8 \cdot 10^{-06}$	$2.7 \cdot 10^{-06}$	$2.7 \cdot 10^{-06}$	$2.6 \cdot 10^{-06}$	$2.6 \cdot 10^{-06}$	$2.5 \cdot 10^{-06}$	$2.7 \cdot 10^{-06}$	$3.0 \cdot 10^{-06}$				
n	0.93	0.94	0.94	0.95	0.95	0.95	0.95	0.95	0.95	0.94	0.94	0.94	0.94	0.93	0.92

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ii. Open Circuit Potential (OCP)

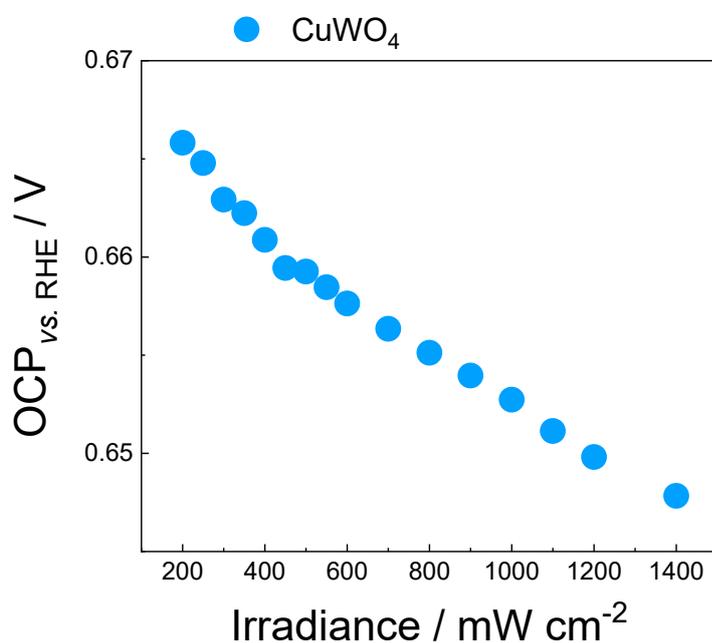


Figure S11. Steady-state OCP at different light intensities for CuWO₄.

OCP measurements were performed until obtaining a steady-state value at different light intensities (from 200 to 1400 mW cm⁻²). In principle, the steady state OCP under intense illumination value approximately corresponds to the flat band potential, which in this case has a value of around 0.64 V_{RHE}.

iii. Current-potential scans under chopped illumination

This method is based on determining the potential at which (for n-type semiconductors) a stable photoanodic response starts, which is approximately equal to the flat band potential. It signals the potential at which the band bending starts (if band edge pinning prevails).³⁴ The measurements were conducted at a slow positive going scan rate (1 mV s⁻¹) under periodically interrupted illumination in 0.1 M Na₂SO₄.

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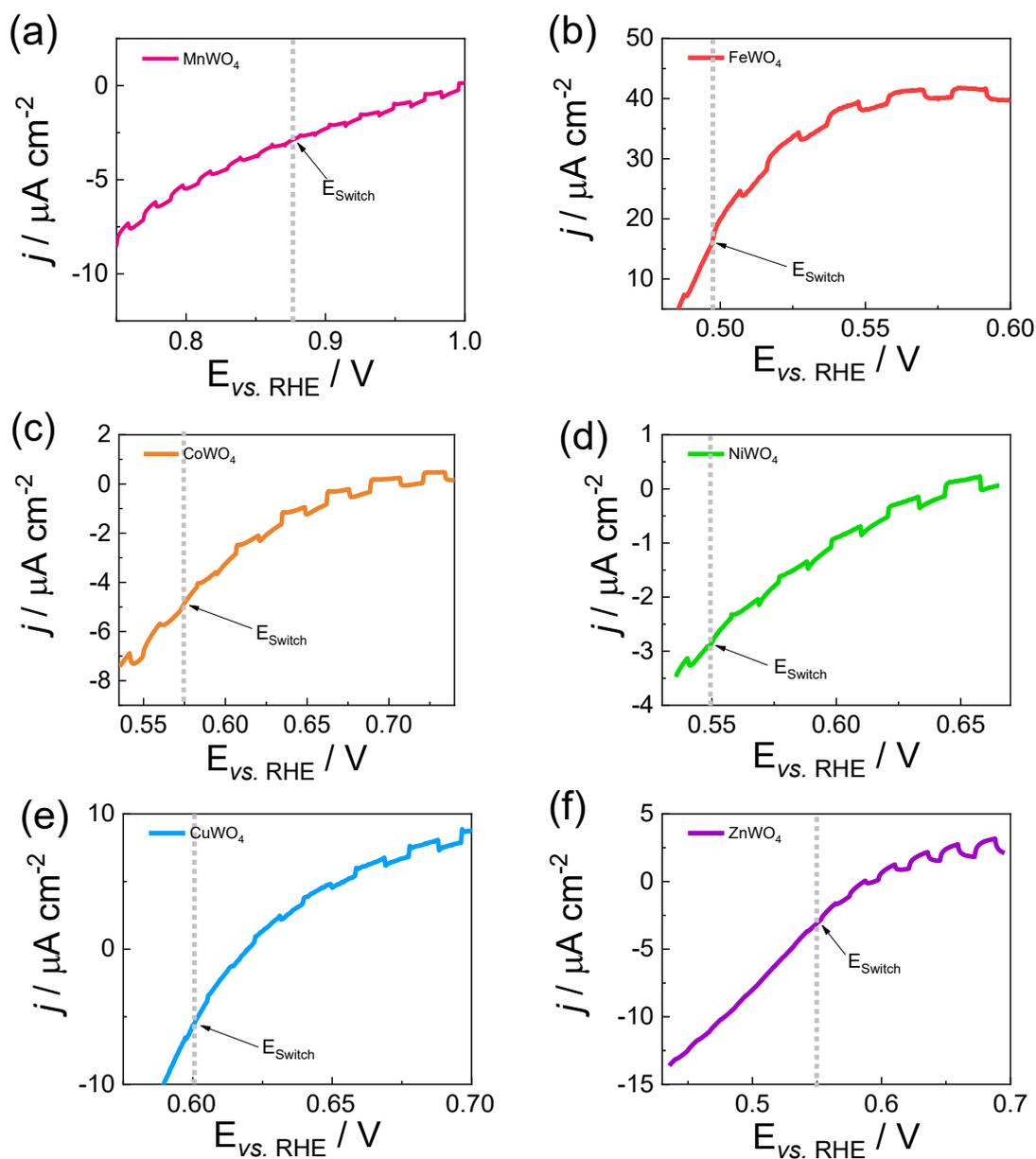


Figure S12. LSV for RWO₄ electrodes in 0.1 M Na₂SO₄ under 1 W cm⁻² chopped illumination for the complete tungstate series: a) Mn, b) Fe, c) Ni, d) Cu and f) Zn. The grey dotted lines indicate the E_{fb} value

14. Thickness and Photoresponse

By adjusting the preparation conditions (number of layers), films of comparable thickness were prepared for the different tungstates (**Table S7**).

Electronic Supplementary Information

Table S7. Film thickness of RWO₄ samples

Sample	Film thickness / μm
MnWO ₄	1.3
FeWO ₄	1.4
CoWO ₄	1.3
NiWO ₄	1.5
CuWO ₄	1.2
ZnWO ₄	1.6

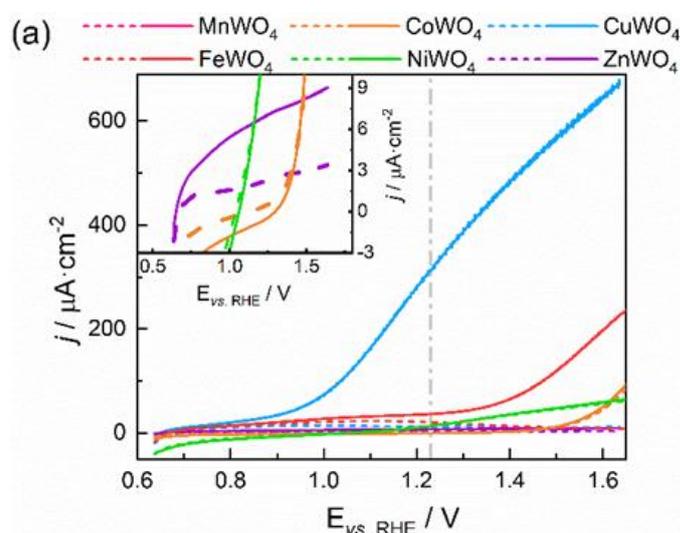


Figure S13. LSVs for RWO₄ electrodes with the thickness of Error! Reference source not found.7 in phosphate buffer solution (pH 7) both in the dark (dashed lines) and under 100 mW cm⁻² SE illumination (solid lines) (Ni, Zn, and Co curves are given in the inset). CuWO₄ has the same photocurrent as in Figure 7a because the thickness is the optimal.

Both **Figure S13.** LSVs for RWO₄ electrodes with the thickness of Error! Reference source not found.7 in phosphate buffer solution (pH 7) both in the dark (dashed lines) and under 100 mW cm⁻² SE illumination (solid lines) (Ni, Zn, and Co curves are given in the inset). CuWO₄ has the same photocurrent as in Figure 7a because the thickness is the optimal.

and **7** show the same trends, with photocurrents that do not significantly change with moderate variations of the film thickness.

15. Theoretical band edge energies

To obtain the theoretical band edge energies represented in **Figure 4**, it was necessary to first calculate the Fermi level by the method proposed by Butler and Ginley³⁵ according to Eq. S10:

$$E_F = (\chi_R \chi_W \chi_O^4)^{\frac{1}{7}} \quad (\text{S10})$$

Electronic Supplementary Information

where χ is the electronegativity of the corresponding element in the Mulliken scale. Then, half of the theoretical band gap (of the corresponding RWO_4) obtained by DFT calculations is either added or subtracted to the Fermi level. This method is only approximate. Deviations from experimental results are not unexpected.

Electronic Supplementary Information

16. Comparison with literature

Table S8. Comparison of RWO₄ electrode related information in this work and in the bibliography, the **irradiation power** in all cases is **100 mW cm⁻²**.

Photoanode	Synthesis Method	Thermal treatment	Electrolyte	Photocurrent density @1.23V _{RHE} / $\mu\text{A cm}^{-2}$	Reference
FTO MnWO ₄ FTO FeWO ₄ FTO CoWO ₄ FTO NiWO ₄ FTO CuWO ₄ FTO ZnWO ₄	Sol-gel	550°C for 2h at 3°C/min	0.1 M KPi	- 41 0.0003 0.0007 315 0.0046	This work
FTO CuWO ₄	Sol-gel	550°C for 2h		20	
FTO FeWO ₄ FTO CoWO ₄ FTO NiWO ₄ FTO CuWO ₄	Polymeric precursors	500°C for 2h at 3°C/min	0.1 M Na ₂ SO ₄	5 21 12.5 30	36
FTO CuWO ₄ FTO NiWO ₄	Hydrothermal	550°C for 2h at 3°C/min	0.1 M KPi	230 90	31
FTO FeWO ₄	Flame synthesis	500°C for 2h	1 M KOH	25	29
FTO MnWO ₄ FTO CuWO ₄	Co-precipitation	500 °C for 30 min at 2 °C/min	0.1 M Na ₂ SO ₄	- 19	37
FTO CoWO ₄	Co-precipitation	500°C for 3h		0.5	13
FTO CuWO ₄	Hydrothermal	500°C for 2h at 3°C/min	0.2 M KPi	380	23
FTO CuWO ₄	Sol-gel	500°C for 2h		380	38
FTO CuWO ₄	Hydrothermal	500°C for 2h		200	39
FTO CuWO ₄	Sol-gel	550°C for 2h	0.1 M KPi	480	40

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17. LSV at different light irradiances

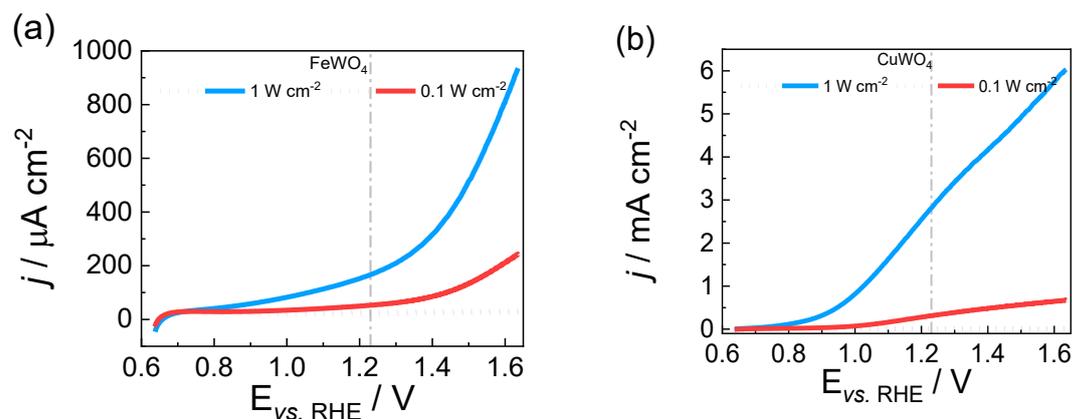


Figure S14. (a), (b) LSVs at 0.1 and 1 W cm⁻² for FeWO₄ and CuWO₄ electrodes, respectively. Broken curves were recorded in the dark.

18. Electrolyte-Electrode (EE) illumination

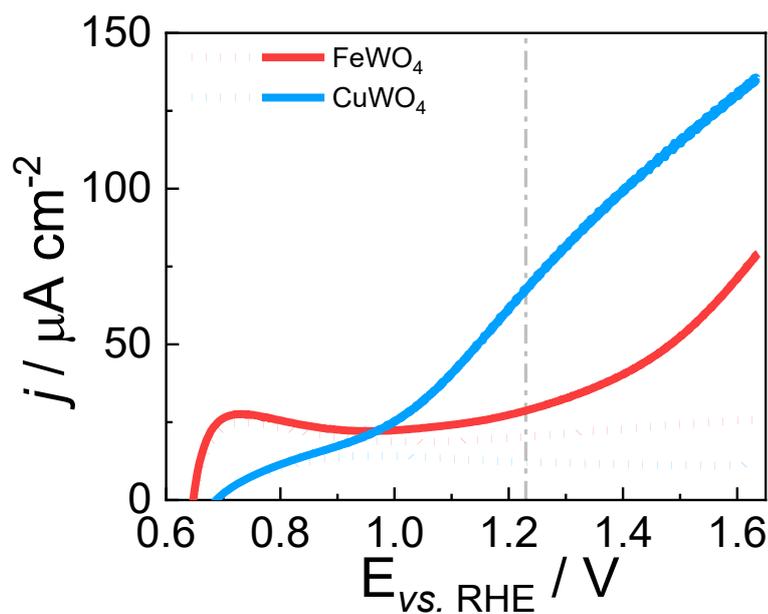


Figure S15. LSV in 0.1 M Na₂SO₄ by EE illumination of the electrodes under 100 mW cm⁻², for Fe and Cu tungstates. Continuous lines under irradiation and broken ones in the dark.

19. CuWO₄ electron lifetime estimate

To obtain the electron lifetime for CuWO₄ (τ), OCP relaxation and CV experiments were carried out in N₂-purged 0.2 M KPi. Electron density at each potential value (n_{ph}) and τ were calculated according to Eqs. S11 and S12, respectively.^{41,42}

Electronic Supplementary Information

$$n_{ph} = \frac{1}{eAd} \int_{E_{OC}^{dark}}^{E_{OC}^{(t)}} \frac{I}{v} dE \quad (S11)$$

$$\tau^{-1} = -\frac{1}{n_{ph}} \frac{dn_{ph}}{dt} \quad (S12)$$

where e is the elementary charge (1.602×10^{-19} C), A is the electrode area (cm^2), d is the thickness of the electrode (cm), I is the current of the CV (A), v is the scan rate of the CV (V s^{-1}), and t is the time (s).

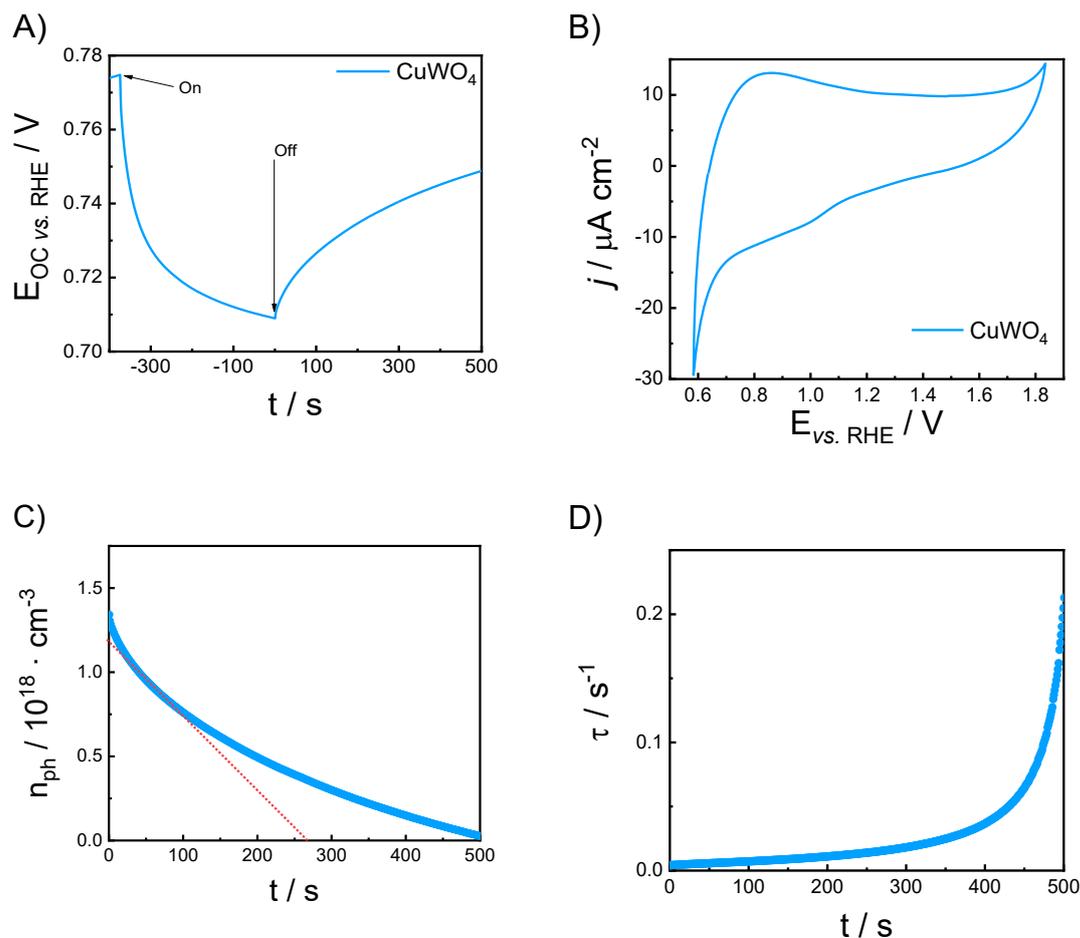


Figure S16. (a) OCP with light chopped on (-350 s) and off (0 s), (b) CV in the dark at 20 mV s^{-1} , (c) electron density (n_{ph}) vs. time, (d) electron lifetime (τ) vs. time (during potential relaxation). All these plots are for a CuWO_4 electrode in an N_2 purged 0.2 M KPi buffer solution.

20. IPCE and APCE

The IPCE was calculated according to Eq. S13:

$$\text{IPCE} = \frac{1239.8 (\text{V nm}) j_{ph} (\text{mA cm}^{-2})}{P_{\text{light}} (\text{mW cm}^{-2}) \lambda (\text{nm})} \quad (S13)$$

IPCE can be related to the efficiencies of the different processes involved in the photoresponse:

Electronic Supplementary Information

$$\text{IPCE} = \eta_{e^-/h^+} \eta_{\text{transport}} \eta_{\text{interface}} \quad (\text{S14})$$

where λ is the wavelength, j_{ph} is the measured photocurrent density at a specific λ , P_{light} is the power of the monochromatic light at a given λ , η_{e^-/h^+} is the fraction of incident photons that are absorbed, giving rise to electron/hole pairs, $\eta_{\text{transport}}$ is the charge transport efficiency within the electrode, and $\eta_{\text{interface}}$ is the interfacial charge transfer efficiency.

The absorbed photon-to-current efficiency (APCE) is calculated according to Eq. S15:

$$\text{APCE} = \frac{\text{IPCE}}{A_\lambda} \quad (\text{S15})$$

APCE can be

$$\text{APCE} = \frac{\text{IPCE}}{\eta_{e^-/h^+}} = \eta_{\text{transport}} \eta_{\text{interface}} \quad (\text{S16})$$

where A_λ is the absorbance at a certain λ .

The short-circuit current density (J_{sc}) can be obtained from the IPCE measurements according to Eq. S17:

$$J_{sc} = \int_{\lambda_2}^{\lambda_1} e \cdot \text{IPCE}(\lambda) \cdot E(\lambda) \cdot \frac{\lambda}{h \cdot c} \cdot d\lambda \quad (17)$$

being e the elementary charge ($1.60 \cdot 10^{-19}$ C), $E(\lambda)$ the spectral irradiance (AM1.5G solar spectrum, $\text{W m}^{-2} \text{nm}^{-1}$), λ the wavelength (nm), h the Planck's constant ($6.63 \cdot 10^{-34}$ J s), and c the speed of light (m s^{-1}).

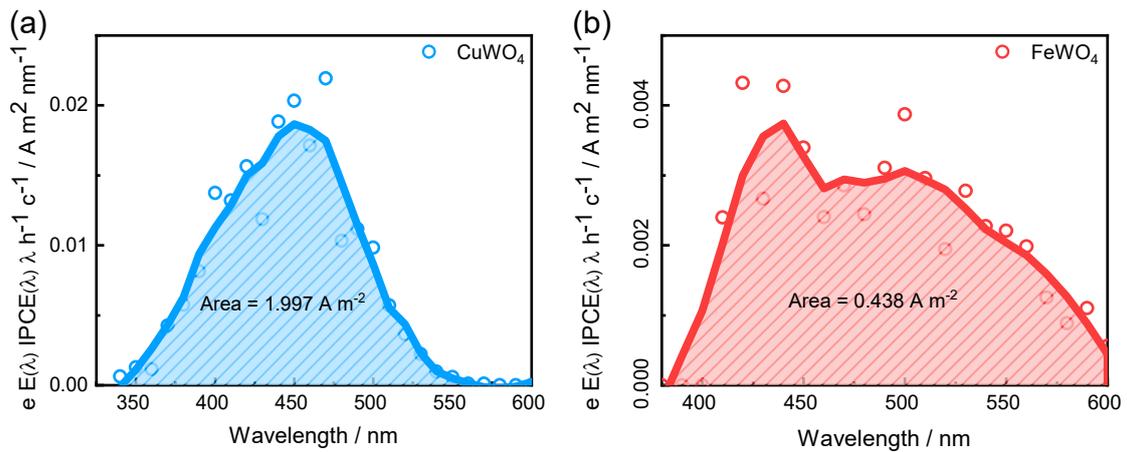


Figure S17. Short-circuit photocurrent density from IPCE values for a) CuWO₄ and b) FeWO₄.

21. Chronoamperometry at different pH values

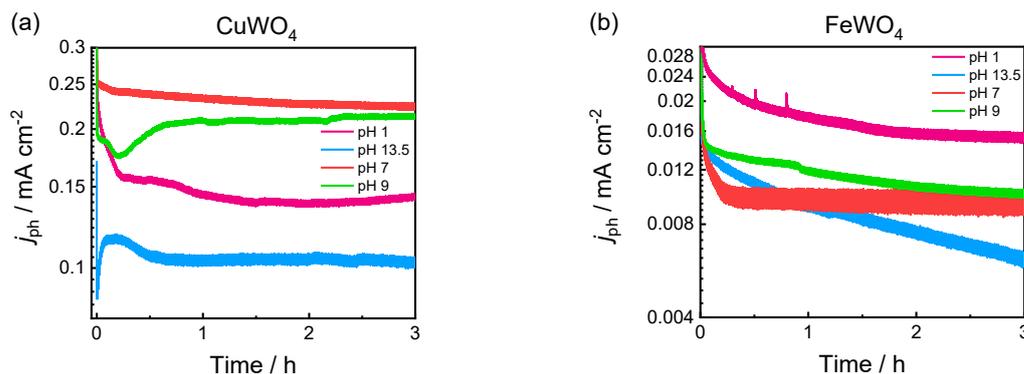


Figure S18. Chronoamperometric curves for CuWO_4 and FeWO_4 electrodes at $1.23 V_{\text{RHE}}$ for different media: $0.1 \text{ M H}_2\text{SO}_4$ (pH 1), 0.1 M KOH (pH 13.5), 0.2 M KPi (pH 7), and 0.1 M KBi (pH 9). *KBi stands for buffer borate, and KPi for buffer phosphate.

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